

Notice of References Cited	Application/Control No. 09/894,653	Applicant(s)/Patent Under Reexamination DEDU-CONSTANTIN ET AL.	
	Examiner Susan Y. Chen	Art Unit 2161	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0149572	07-2005	Kanai et al.	707/104.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"X-Schema", Mark Birbeck, June 23, 1999, http://mailman.ic.ac.uk/pipermail/xml-dev/1999-June/013125.html
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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